

MAR 22 2005

500.43175X00/W1215-01ER

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Susumu KASUKABE *et al.*
Serial No. : 10/676,609
Filed : 2 October 2003
For : PROBE SHEET, PROBE CARD, SEMICONDUCTOR TEST
EQUIPMENT AND SEMICONDUCTOR DEVICE FABRICATION
Group AU : 2829
Examiner : M.N. Tang
Conf. No. : 7923

AMENDMENT**Mail Stop Amendment**

Commissioner for Patents

POB 1450

Alexandria, Virginia 22313-1450

22 March 2005

Sir:

In response to the Office Action mailed 22 September 2004 in connection with the above-identified application, the following amendments and remarks are respectfully submitted.

In accordance with 37 CFR §1.121 in the Final Rule effective 30 July 2003, and as revised in the Final Rule effective 21 October 2004, each section of amendment begins on a new page, and changes are shown by strike-through (or double brackets where appropriate) and underlining to indicate deletions and additions, respectively. A complete listing of all claims ever presented in the application is given with the current status of each claim, and only the text of all pending and withdrawn claims is presented in full, with those pending/withdrawn claims not being amended herein being presented in clean version.

03/23/2005 BONNER 00000037 10676609